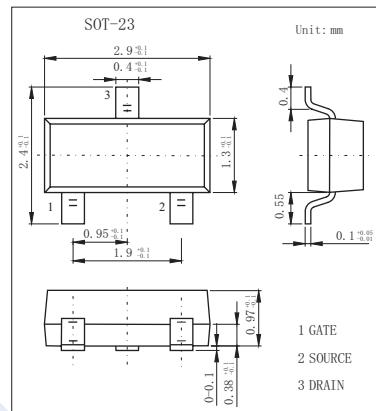
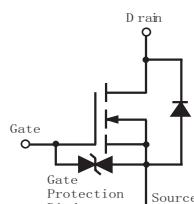


N-Channel Enhancement MOSFET

2N7002K

■ Features

- Low On-Resistance: $R_{DS(ON)}$
- Low Gate Threshold Voltage
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- ESD Protected 2KV HBM



■ Absolute Maximum Ratings $T_a=25^\circ\text{C}$

| Parameter | Symbol | Rating | Unit |
|---|------------|------------|---------------------------|
| Drain-Source Voltage | V_{DS} | 60 | V |
| Gate-Source Voltage -Continuous | V_{GS} | ± 20 | |
| Drain Current -Continuous (Note:1) | I_D | 300 | mA |
| -Pulsed | | 800 | |
| Power Dissipation (Note 1) | P_D | 350 | mW |
| Thermal Resistance.Junction- to-Ambient | R_{thJA} | 357 | $^\circ\text{C}/\text{W}$ |
| Junction Temperature | T_J | 150 | $^\circ\text{C}$ |
| Storage Temperature Range | T_{stg} | -55 to 150 | |

Notes: 1. Device mounted on FR-4 PCB.

■ Electrical Characteristics $T_a = 25^\circ\text{C}$

| Parameter | Symbol | Test Conditions | Min | Typ | Max | Unit |
|--|--------------|--|-----|-----|----------|---------------|
| Drain-Source Breakdown Voltage (Note.2) | V_{DSS} | $I_D=100 \mu\text{A}$, $V_{GS}=0\text{V}$ | 60 | | | V |
| Zero Gate Voltage Drain Current (Note.2) | I_{DSS} | $V_{DS}=60\text{V}$, $V_{GS}=0\text{V}$ | | | 1 | μA |
| Gate-Body Leakage Current (Note.2) | I_{GSS} | $V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$ | | | ± 10 | μA |
| Gate Threshold Voltage (Note.2) | $V_{GS(th)}$ | $V_{DS} = 10\text{V}$, $I_D = 1\text{mA}$ | 1 | 1.6 | 2.5 | V |
| Static Drain-Source On-Resistance (Note.2) | $R_{DS(on)}$ | $V_{GS}=10\text{V}$, $I_D=500\text{mA}$ | | | 2 | Ω |
| | | $V_{GS}=10\text{V}$, $I_D=50\text{mA}$ | | | 3 | |
| Forward Transfer Admittance (Note.2) | $ Y_{fs} $ | $V_{GS}=10\text{V}$, $I_D=200\text{mA}$ | 80 | | | ms |
| Input Capacitance | C_{iss} | $V_{GS}=0\text{V}$, $V_{DS}=25\text{V}$, $f=1\text{MHz}$ | | | 50 | pF |
| Output Capacitance | C_{oss} | | | | 25 | |
| Reverse Transfer Capacitance | C_{rss} | | | | 5 | |
| Total Gate Charge | Q_g | $V_{GS}=4.5\text{V}$, $V_{DS}=15\text{V}$, $I_D=200\text{mA}$ | | | 0.8 | nC |
| Turn-On DelayTime | $t_{d(on)}$ | $I_D=200\text{mA}$, $V_{DS}=30\text{V}$, $R_G=10\Omega$, $V_{GEN}=10\text{V}$, $R_L=150\Omega$ | | | 20 | ns |
| Turn-Off DelayTime | $t_{d(off)}$ | | | | 40 | |

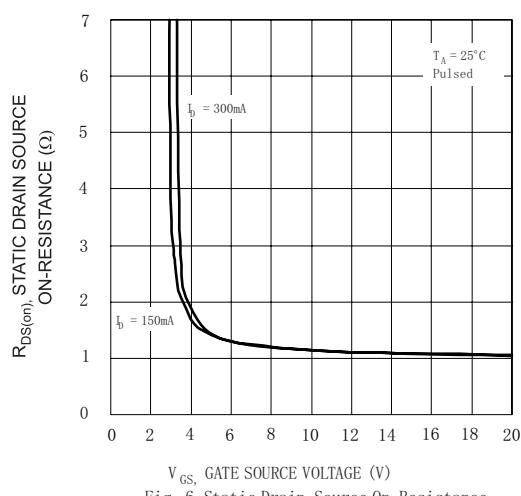
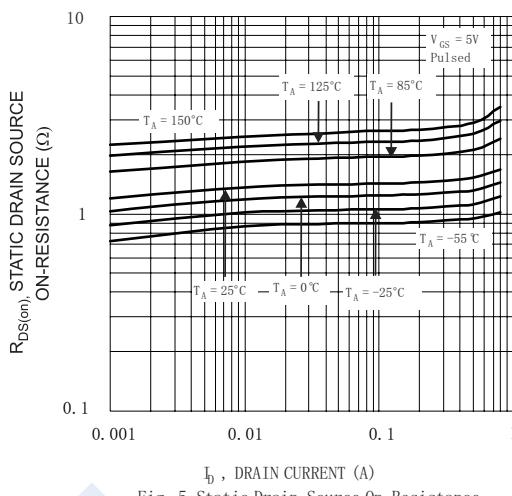
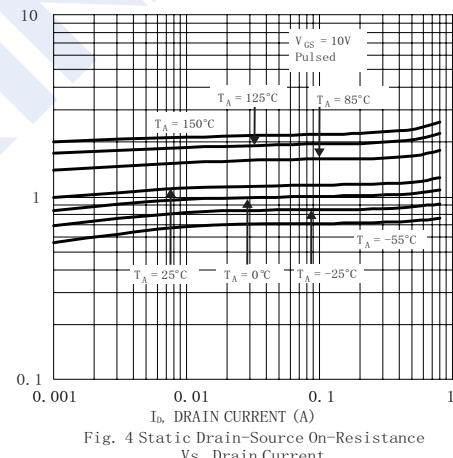
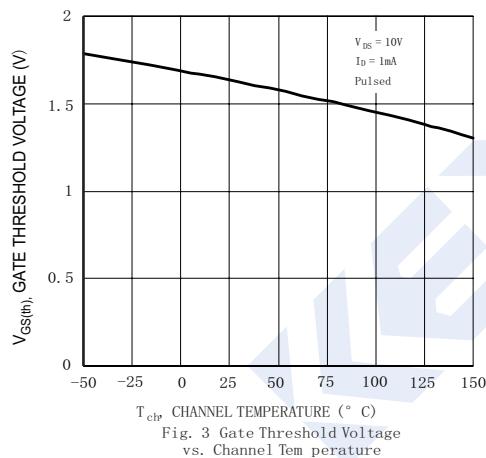
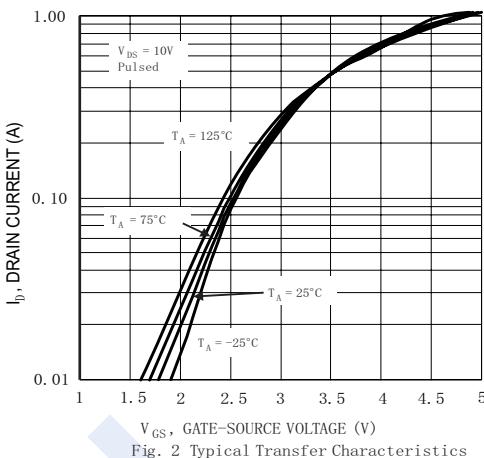
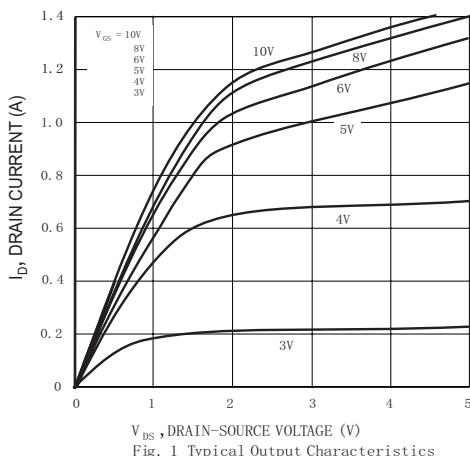
Note: 2. Short duration test pulse used to minimize self-heating effect.

■ Marking

| | |
|---------|------|
| Marking | K72Ω |
|---------|------|

2N7002K

■ Typical Characteristics



2N7002K